

<b>Notice of References Cited</b>	Application/Control No. <b>09/751,859</b>	Applicant(s)/Patent Under Reexam <b>Nabe et al.</b>	
	Examiner <b>T. Chen</b>	Art Unit <b>2171</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	6,546,545	4/2003	Honarvar et al.	717	100
B					
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**FOREIGN PATENT DOCUMENTS**

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